Jochen Bruckbauer

List of Publications by Citations

37 papers	454 citations	12 h-index	20 g-index
37 ext. papers	506 ext. citations	4.6 avg, IF	3.19 L-index

#	Paper	IF	Citations
37	An organic down-converting material for white-light emission from hybrid LEDs. *Advanced Materials*, **2014**, 26, 7290-4	24	95
36	High resolution cathodoluminescence hyperspectral imaging of surface features in InGaN/GaN multiple quantum well structures. *Applied Physics Letters*, **2011**, 98, 141908	3.4	68
35	High-resolution cathodoluminescence hyperspectral imaging of nitride nanostructures. *Microscopy and Microanalysis*, **2012**, 18, 1212-9	0.5	42
34	Coincident electron channeling and cathodoluminescence studies of threading dislocations in GaN. *Microscopy and Microanalysis*, **2014**, 20, 55-60	0.5	23
33	Cool to warm white light emission from hybrid inorganic/organic light-emitting diodes. *Journal of Materials Chemistry C*, **2016**, 4, 11499-11507	7.1	22
32	Influence of substrate miscut angle on surface morphology and luminescence properties of AlGaN. *Applied Physics Letters*, **2014**, 104, 092114	3.4	20
31	Electron channelling contrast imaging for III-nitride thin film structures. *Materials Science in Semiconductor Processing*, **2016**, 47, 44-50	4.3	19
30	Linear oligofluorene-BODIPY structures for fluorescence applications. *Journal of Materials Chemistry C*, **2013**, 1, 2249	7.1	18
29	Influence of stress on optical transitions in GaN nanorods containing a single InGaN/GaN quantum disk. *Journal of Applied Physics*, **2014**, 116, 174305	2.5	16
28	Implementing fluorescent MOFs as down-converting layers in hybrid light-emitting diodes. *Journal of Materials Chemistry C*, **2019**, 7, 2394-2400	7.1	15
27	Electron channeling contrast imaging studies of nonpolar nitrides using a scanning electron microscope. *Applied Physics Letters*, **2013**, 102, 142103	3.4	15
26	Colour tuning in white hybrid inorganic/organic light-emitting diodes. *Journal Physics D: Applied Physics*, **2016**, 49, 405103	3	13
25	Determining GaN Nanowire Polarity and its Influence on Light Emission in the Scanning Electron Microscope. *Nano Letters*, **2019**, 19, 3863-3870	11.5	11
24	Probing light emission from quantum wells within a single nanorod. *Nanotechnology*, **2013**, 24, 365704	3.4	10
23	Spatially-resolved optical and structural properties of semi-polar [Formula: see text] Al Ga N with x up to 0.56. *Scientific Reports*, **2017**, 7, 10804	4.9	10
22	Cathodoluminescence hyperspectral imaging of trench-like defects in InGaN/GaN quantum well structures. *Journal Physics D: Applied Physics*, **2014**, 47, 135107	3	9
21	Scanning electron microscopy as a flexible technique for investigating the properties of UV-emitting nitride semiconductor thin films. *Photonics Research*, **2019**, 7, B73	6	6

20	Cathodoluminescence studies of chevron features in semi-polar (112□2) InGaN/GaN multiple quantum well structures. *Journal of Applied Physics*, **2018**, 123, 174502	2.5	6
19	Optical investigation of semi-polar (11-22) AlxGa1-xN with high Al composition. *Applied Physics Letters*, **2017**, 110, 091102	3.4	5
18	A poly(urethane)-encapsulated benzo[2,3-d:6,7-d?]diimidazole organic down-converter for green hybrid LEDs. *Materials Chemistry Frontiers*, **2020**, 4, 1006-1012	7.8	5
17	A systematic comparison of polar and semipolar Si-doped AlGaN alloys with high AlN content. *Journal Physics D: Applied Physics*, **2021**, 54, 035302	3	5
16	Optical Properties of GaN Nanorods Containing a Single or Multiple InGaN Quantum Wells. *Japanese Journal of Applied Physics*, **2013**, 52, 08JE11	1.4	4
15	Structural and luminescence imaging and characterisation of semiconductors in the scanning electron microscope. *Semiconductor Science and Technology*, **2020**, 35, 054001	1.8	3
14	Light-Emitting Diodes: An Organic Down-Converting Material for White-Light Emission from Hybrid LEDs (Adv. Mater. 43/2014). *Advanced Materials*, **2014**, 26, 7415-7415	24	3
13	Monolithic multiple colour emission from InGaN grown on patterned non-polar GaN. *Scientific Reports*, **2019**, 9, 986	4.9	3
12	Microscopy of defects in semiconductors **2019**, 345-416		3
11	Self-assembly of ordered wurtzite/rock salt heterostructures□A new view on phase separation in MgxZn1□xO. *Journal of Applied Physics*, **2015**, 118, 045706	2.5	2
10	Applications of electron channeling contrast imaging for characterizing nitride semiconductor thin films. *Microscopy and Microanalysis*, **2012**, 18, 684-685	0.5	1
9	You Do What in Your Microprobe?! The EPMA as a Multimode Platform for Nitride Semiconductor Characterization. *Microscopy and Microanalysis*, **2018**, 24, 2026-2027	0.5	1
8	Crystalline grain engineered CsPbIBr2 films for indoor photovoltaics. *Applied Surface Science*, **2022**, 592, 152865	6.7	1
7	Luminescence behavior of semipolar (10 1 □1) InGaN/GaN □ow-tie□structures on patterned Si substrates. *Journal of Applied Physics*, **2020**, 127, 035705	2.5	0
6	Influence of micro-patterning of the growth template on defect reduction and optical properties of non-polar (1120) GaN. *Journal Physics D: Applied Physics*, **2021**, 54, 025107	3	0
5	Influence of an InGaN superlattice pre-layer on the performance of semi-polar (11-22) green LEDs grown on silicon. *Scientific Reports*, **2020**, 10, 12650	4.9	0
4	Cathodoluminescence Hyperspectral Imaging of Nitride Semiconductors: Introducing New Variables. *Microscopy and Microanalysis*, **2014**, 20, 906-907	0.5	
3	Electron Channeling Contrast Imaging of Defects in III-Nitride Semiconductors. *Microscopy and Microanalysis*, **2014**, 20, 1024-1025	0.5	

2	Advances in electron channelling contrast imaging and electron backscatter diffraction for imaging and analysis of structural defects in the scanning electron microscope. *IOP Conference Series: Materials Science and Engineering*, **2020**, 891, 012023	0.4
1	Reprint of: Electron channelling contrast imaging for III-nitride thin film structures. *Materials Science in Semiconductor Processing*, **2016**, 55, 19-25	4.3